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## **IMAGES ARE BEST AVAILABLE COPY.**

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**Amendment to the Claims:**

Please amend the claims as indicated below:

1. (Currently amended) A system to capture an ~~one or more~~ image[[s]] ~~[[of]]~~ from a semiconductor processing chamber, comprising:
  - a radiation source to ~~generate radiation to~~ illuminate the processing chamber;
  - at least one sensor that can detect at least one triggering condition in the processing chamber, said at least one sensor functionally connected with a camera; and
  - [[a]] the camera coupled to the process chamber [[and]] wherein the camera adapted to can receive the radiation reflected from the chamber and can capture the image upon a trigger from the at least one sensor upon the occurrence of at least one triggering condition.
2. (Original) The system of claim 1, wherein the radiation source comprises one or more lamps.
3. (Currently amended) The system of claim 1, further comprising a processor operatively coupled to the camera, wherein a first function of the processor is to control a plurality of camera settings, and a second function of the processor is to monitor at least one process parameter.
4. (Currently amended) The system of claim 3, further comprising a data storage device operatively coupled to the processor and the camera, the data storage device can ~~[[to]]~~ store the image[[s]] from the camera.
5. (Currently amended) The system of claim 3, further comprising a network ~~adapter~~ adaptor card operatively coupled to the processor.
6. (Currently amended) The system of claim 5, wherein the network adaptor ~~adapter~~ card is also operatively coupled to a wide area network.

7. (Currently amended) The system of claim 5, wherein the network ~~adaptor~~ adapter card is also operatively coupled to the Internet.
8. (Currently amended) The system of claim 7, further comprising a server operatively coupled to the Internet and ~~adapted to~~ which can receive data from the camera.
9. (Currently amended) The system of claim 1, wherein ~~[[the]]~~ a server operatively connected with a wide area network receives and stores multimedia data from the camera and sends the multimedia data to a remote viewer on demand.
10. (Currently amended) The system of claim 1, wherein the camera captures at least one of a still image ~~[[or]]~~ and a video.
11. (Cancelled)
12. (Currently amended) The system of claim ~~[[1]]~~ 3, further comprising a ~~process~~ sensor operatively coupled to the processor, wherein the sensor can ~~[[to]]~~ capture process data ~~in addition to camera data~~.
13. (Currently amended) The system of claim 1, further comprising a motor functionally coupled to the camera, wherein the motor can ~~[[to]]~~ cause the camera to pan the processing chamber ~~camera~~.
14. (Currently amended) The system of claim 1, further comprising a view port in order to view ~~coupled to~~ the processing chamber.
15. (Currently amended) The system of claim 14, further comprising a light pipe coupling the camera to the view port, wherein the light pipe projects from an exterior of the processing chamber to an interior of the processing chamber to allow the camera to capture the image from the interior of the processing chamber.

16. (Currently amended) The system of claim 1, further comprising a light pipe projecting from ~~the outside~~ an exterior of the processing chamber to ~~the inside~~ an interior of the processing chamber, wherein the light pipe can allow[[ing]] the camera to capture the ~~radiation illuminating~~ image from the ~~inside of~~ interior of the processing chamber.
17. (Currently amended) The system of claim 1, wherein the camera captures radiation ~~illuminating from an exterior of~~ outside the processing chamber.
18. (Currently amended) The system of claim 1, wherein the radiation source is an ambient radiation.
19. (Currently amended) The system of claim 1, wherein the radiation source is an infrared light source coupled to the processing chamber.
20. (Currently amended) The system of claim 1, wherein the radiation source is a visible light source coupled to the processing chamber.
21. (Currently amended) The system of claim 1, further comprising an imaging processor coupled to the camera to detect ~~one or more predefined criteria~~ the at least one triggering condition.
22. (Currently amended) The system of claim 21, wherein the imaging processor determines the position of at least one ~~one or more~~ component[[s]] in the processing chamber.
23. (Currently amended) The system of claim 22, wherein the at least one component[[s]] ~~include~~ is at least one of a wafer, a robot arm, a wafer cassette, a wafer support, and ~~and~~ [[or]] a chuck.

24. (Currently amended) An apparatus to capture at least one ~~one or more~~ image[[s]]  
[[of]] from a semiconductor processing system with at least one ~~one or more~~ transfer  
chamber[[s]] and at least one ~~one or more~~ processing chamber[[s]], the apparatus  
comprising:

a radiation source to ~~generate radiation to~~ illuminate the semiconductor  
processing system; and

a camera functionally coupled to the semiconductor processing system and  
adapted to receive radiation ~~reflected~~ from the semiconductor processing system, wherein  
the camera captures the at least one image upon an occurrence of at least one triggering  
condition.

25. (Currently amended) A system to capture ~~one or more images~~ an image from [[of]] a  
semiconductor processing chamber based on at least one trigger condition, the system  
comprising:

a radiation source to ~~generate radiation to~~ illuminate the processing chamber;  
[[and]]

a camera which can receive the radiation from the processing chamber;

at least one sensor to detect at least one triggering condition, the at least one  
sensor operatively connected with the camera to trigger the camera based on the  
triggering condition, wherein the at least one sensor causes the camera to switch from a  
first idle mode to a second triggered mode, wherein the camera is triggered to capture the  
image from the semiconductor processing chamber;

the processor, operatively connected with a camera;

~~the camera coupled to the process chamber and adapted to receive the~~  
~~radiation reflected from the chamber~~

~~a processor coupled to the camera;~~

a data storage device operatively coupled to the processor and the  
camera to store an image[[s]] from the camera, said image captured while the camera is  
in the triggered mode;

a network ~~adaptor~~ adapter card operatively connecting ~~coupled~~ to the processor ~~with and the Internet~~ a network; and

a server operatively coupled to the network and ~~adapted~~ to receive and store ~~[[data]]~~ the image from the camera, the server sending the image ~~multimedia data~~ to a remote viewer on the ~~Internet~~ network.

26. (Currently amended) A method for viewing a semiconductor processing operation, the method comprising:

illuminating a processing chamber ~~with radiation~~; ~~[[and]]~~

using at least one sensor for the processing chamber to detect at least one triggering condition and to trigger a camera upon occurrence of the at least one triggering condition;

detecting the at least one triggering condition in the processing operation; and

capturing with the camera at least one ~~one or more~~ view[[s]] of the processing chamber using a camera, wherein the capturing step is based on the occurrence of the at least one triggering condition.

27. (Currently amended) The method of claim 26, further comprising analyzing the views to determine a ~~locate~~ the position of at least one ~~one or more~~ component[[s]] in the processing chamber.

28. (Currently amended) The method of claim 27, wherein the at least one component[[s]] is selected from the group consisting of ~~include~~ a wafer, a robot arm, a wafer cassette, a wafer support, or a chuck.

29. (Currently amended) The method of claim 26, further comprising storing the at least one view[[s]] on a remote server.

30. (Currently amended) The method of claim 29, further comprising streaming the at least one view[[s]] from the remote server to at least one ~~one or more~~ remote

viewer[[s]].

31. (Cancelled)

32. (Currently amended) The method of claim 31 ~~26~~, wherein the at least one triggering condition criteria include is selected from the group consisting of a component movement, a component failure, an out-of-range condition, ~~[[or]]~~ and a predefined time interval.

33. (Currently amended) A method for remotely viewing a semiconductor processing operation, comprising:

illuminating a chamber ~~with radiation~~;

capturing at least one ~~one or more~~ view[[s]] of the chamber using a camera;

storing the at least one view[[s]] on a remote server; and

streaming the at least one view[[s]] from the remote server to at least one ~~one or more~~ remote viewer[[s]], wherein the at least one view[[s are]] is captured based on the occurrence of ~~one or more~~ at least one predetermined triggering condition criteria.

34. (New) A system to capture an image of a semiconductor processing chamber when a triggering condition occurs, the system comprising:

a radiation source to illuminate the chamber;

a camera positioned to receive radiation from the processing chamber and to capture the image;

a sensor to capture processing data; and

a processor functionally coupled with the camera and with the sensor, said processor to control a plurality of camera settings, wherein the camera remains idle until the processor detects at least one said triggering condition and the camera is triggered to capture the image of the processing chamber.

35. (New) The system of claim 34 wherein the image comprises multimedia data, and

said multimedia data is stored by a data storage device operatively connected with the camera and the processor.

36. (New) The system of claim 35 wherein a central server over a wide area network is functionally associated with the data storage device to upload the plurality of multimedia data stored by the data storage device.
37. (New) The system of claim 33 wherein said plurality of triggering conditions are selected from the group consisting of a movement of a component, a failure of a component, an out-of-range condition, and a predefined time interval.
38. (New) The system of claim 37 wherein the component is at least one of a wafer, a robot arm, a wafer cassette, a wafer support, and a chuck.
39. (New) A system to capture an image from a semiconductor processing chamber when a triggering condition occurs, the system comprising:
- a radiation source to illuminate the chamber;
  - a camera positioned to receive radiation from the processing chamber and to capture the image;
  - a sensor adapted to capture a triggering condition;
  - a processor functionally coupled with the camera and with the process sensor, said processor used to monitor processing data and to control a plurality of camera settings, wherein the camera remains idle until the processor detects at least one said triggering condition and the camera is triggered to capture the image of the processing chamber; and
  - a server that can receive the image from the camera, the server also coupled to a wide are network.
40. (New) A method to monitor a semiconductor processing chamber to capture an image from the processing chamber based on at least one predetermined triggering



condition, the method comprising:

- illuminating the processing chamber;
- defining a triggering condition to cause a camera to capture the image of the processing chamber;
- monitoring processing with a sensor;
- detecting said triggering conditions;
- communicating the triggering condition to the camera;
- causing the camera to capture the image of the processing chamber; and
- storing the image on a data storage device.

41. (New) The method of claim 40 wherein the method further comprises loading the image onto a remote server.
42. (New) The method of claim 41 wherein the method further comprises accessing remotely the image to assess at least one processing chamber condition during the triggering condition.
43. (New) The method of claim 40 wherein the method further comprises accessing the image from a server.
44. (New) The method of claim 40 further comprising annotating the image.
45. (New) The method of claim 44 wherein the annotating step further comprises annotating verbally.
46. (New) The method of claim 44 wherein the annotating step further comprises annotating textually.
47. (New) A system to capture an image from a semiconductor processing chamber, the system comprising:

at least one sensor that can detect at least one triggering condition in the processing chamber, said at least one sensor functionally connected with a camera; and the camera coupled to the processing chamber and wherein the camera can capture the image upon a trigger signal from the at least one sensor upon the occurrence of the at least one triggering condition.

48. (New) A system to capture an image from a semiconductor processing chamber, the system comprising:

at least one sensor that can detect at least one triggering condition in the processing chamber, said at least one sensor functionally connected with a camera;

the camera coupled to the processing chamber and wherein the camera can capture the image upon a triggering signal from the at least one sensor upon the occurrence of at least one triggering condition; and

a network with a remote monitoring device, wherein said remote monitoring device can communicate with the camera and receives the image on said network.

49. (New) A system to capture an image from a semiconductor processing chamber, the system comprising:

at least one sensor that can detect at least on triggering condition in the processing chamber, said at least one sensor functionally connected with a camera;

a light pipe; and

the camera coupled to the processing chamber with said light pipe and wherein the camera can capture the image through the light pipe upon a triggering signal from the at least one sensor upon the occurrence of at least one triggering condition.